

Searched 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10531299	KIM ET AL.
	Examiner Jaisle, Cecilia M	Art Unit 1624

Class	SubClass	Date	Examiner
U.S. Patent and Trademark Office		Part of Paper No.:	

Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10531299	KIM ET AL.
	Examiner Jaisle, Cecilia M	Art Unit 1624

Notes	Date	Examiner
Searched in STN by STIC	07/12/2006	<i>Cecilia Jaile</i>
Inventor Search done	7/19/06	<i>Cecilia Jaile</i>
U.S. Patent and Trademark Office		Part of Paper No.:

Interference Searched	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10531299	KIM ET AL.
	Examiner Jaisle, Cecilia M	Art Unit 1624

Class	SubClass	Date	Examiner
U.S. Patent and Trademark Office			Part of Paper No.: